

RoHS Compliant Product
A suffix of "-C" specifies halogen free

DESCRIPTION

The SSU63N06S-C is the highest performance trench N-Ch MOSFETs with extreme high cell density, which provide excellent $R_{DS(ON)}$ and gate charge for most of the synchronous buck converter applications .

The SSU63N06S-C meet the RoHS and Green Product requirement with full function reliability approved.

FEATURES

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent dv/dt effect decline
- Green Device Available

MARKING

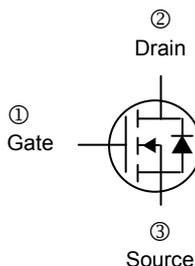
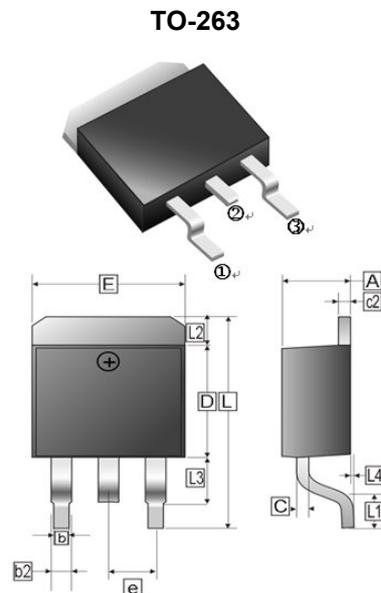


PACKAGE INFORMATION

| Package | MPQ | Leader Size |
|---------|------|-------------|
| TO-263 | 0.8K | 13 inch |

ORDER INFORMATION

| Part Number | Type |
|-------------|---------------------------------|
| SSU63N06S-C | Lead (Pb)-free and Halogen-free |



| REF. | Millimeter | | REF. | Millimeter | |
|------|------------|-------|------|------------|------|
| | Min. | Max. | | Min. | Max. |
| A | 4.00 | 4.87 | c2 | 1.07 | 1.65 |
| b | 0.51 | 1.01 | b2 | 1.34 | REF |
| L4 | 0.00 | 0.30 | D | 8.0 | 9.65 |
| C | 0.30 | 0.74 | e | 2.54 | REF |
| L3 | 1.50 | REF | L | 14.6 | 16.1 |
| L1 | 2.5 | REF | L2 | 1.27 | REF |
| E | 9.60 | 10.67 | | | |

ABSOLUTE MAXIMUM RATINGS ($T_A=25^\circ\text{C}$ unless otherwise specified)

| Parameter | Symbol | Rating | Unit | |
|---|-------------------------|----------|-----------------------------|---|
| Drain-Source Voltage | V_{DS} | 60 | V | |
| Gate-Source Voltage | V_{GS} | ± 20 | V | |
| Continuous Drain Current ¹ @ $V_{GS}=10\text{V}$ | $T_C=25^\circ\text{C}$ | 63 | A | |
| | $T_C=100^\circ\text{C}$ | 45 | | |
| Pulsed Drain Current ² | I_{DM} | 180 | A | |
| Power Dissipation | $T_C=25^\circ\text{C}$ | P_D | 79 | W |
| Operating Junction and Storage Temperature | T_J, T_{STG} | -55~175 | $^\circ\text{C}$ | |
| Thermal Resistance Rating | | | | |
| Thermal Resistance Junction-Ambient ¹ | $R_{\theta JA}$ | 65 | $^\circ\text{C} / \text{W}$ | |
| Thermal Resistance Junction-Case ¹ | $R_{\theta JC}$ | 1.9 | $^\circ\text{C} / \text{W}$ | |

ELECTRICAL CHARACTERISTICS ($T_J=25^\circ\text{C}$ unless otherwise specified)

| Parameter | Symbol | Min. | Typ. | Max. | Unit | Test Conditions |
|--|---------------|------|------|-----------|------------|---|
| Drain-Source Breakdown Voltage | $V_{(BR)DSS}$ | 60 | - | - | V | $V_{GS}=0V, I_D=250\mu A$ |
| Gate-Threshold Voltage | $V_{GS(th)}$ | 1 | - | 2.4 | V | $V_{DS}=V_{GS}, I_D=250\mu A$ |
| Forward Transconductance | g_{fs} | - | 26 | - | S | $V_{DS}=5V, I_D=20A$ |
| Gate-Source Leakage Current | I_{GSS} | - | - | ± 100 | nA | $V_{GS}=\pm 20V, V_{DS}=0V$ |
| Drain-Source Leakage Current | I_{DSS} | - | - | 1 | μA | $V_{DS}=48V, V_{GS}=0V, T_J=25^\circ\text{C}$ |
| | | - | - | 100 | | $V_{DS}=48V, V_{GS}=0V, T_J=100^\circ\text{C}$ |
| Static Drain-Source On-Resistance ³ | $R_{DS(ON)}$ | - | 7 | 8.7 | m Ω | $V_{GS}=10V, I_D=20A$ |
| | | - | 9.7 | 12.7 | | $V_{GS}=4.5V, I_D=10A$ |
| Gate Resistance | R_g | - | 1.5 | - | Ω | $V_{DS}=V_{GS}=0V, f=1\text{MHz}$ |
| Total Gate Charge (4.5V) | Q_g | - | 12 | - | nC | $I_D=20A$ $V_{DD}=30V$ $V_{GS}=10V$ |
| Total Gate Charge | Q_g | - | 24 | - | | |
| Gate-Source Charge | Q_{gs} | - | 5 | - | | |
| Gate-Drain Change | Q_{gd} | - | 3 | - | | |
| Turn-on Delay Time | $T_{d(on)}$ | - | 9 | - | nS | $V_{DD}=30V$ $I_D=20A$ $V_{GS}=10V$ $R_G=10\Omega$ |
| Rise Time | T_r | - | 4 | - | | |
| Turn-off Delay Time | $T_{d(off)}$ | - | 29 | - | | |
| Fall Time | T_f | - | 4 | - | | |
| Input Capacitance | C_{iss} | - | 1620 | - | pF | $V_{GS}=0V$ $V_{DS}=30V$ $f=1\text{MHz}$ |
| Output Capacitance | C_{oss} | - | 415 | - | | |
| Reverse Transfer Capacitance | C_{rss} | - | 3 | - | | |
| Source-Drain Diode | | | | | | |
| Diode Forward Voltage ³ | V_{SD} | - | - | 1.2 | V | $I_F=10A, V_{GS}=0V$ |
| Reverse Recovery Time | T_{rr} | - | 30 | - | ns | $I_F=20A, V_R=30V,$ $di_F/dt=300A/\mu s$ |
| Reverse Recovery Charge | Q_{rr} | - | 43 | - | nC | |

Notes:

1. The data tested by surface mounted on a 1 inch² FR-4 board with 20Z copper.
2. The Pulse width limited by maximum junction temperature, Pulse Width $\leq 300\mu s$, Duty Cycles $\leq 2\%$
3. The Pulse Test : Pulse Width $\leq 300\mu s$, Duty Cycles $\leq 2\%$

CHARACTERISTIC CURVES

Fig 1. Typical Output Characteristics

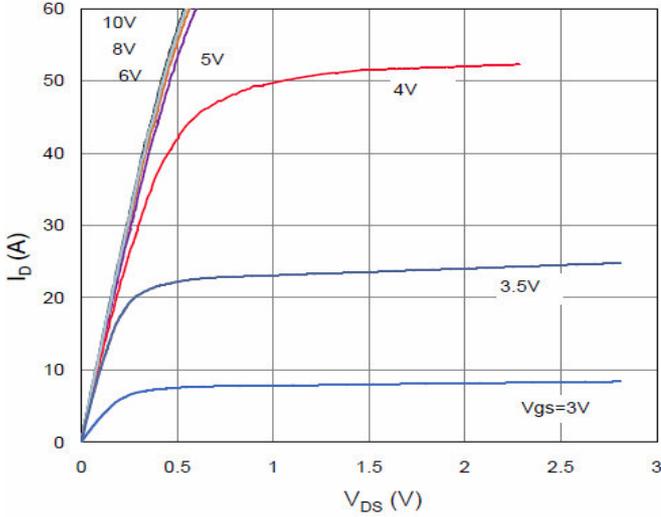


Figure 2. On-Resistance vs. Gate-Source Voltage

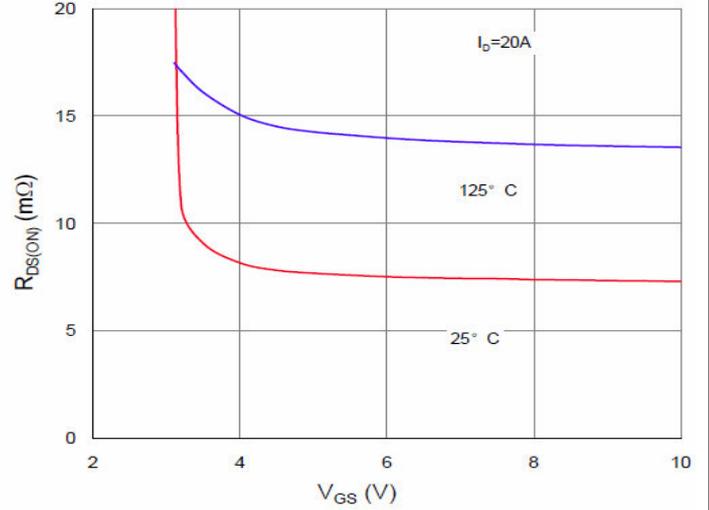


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

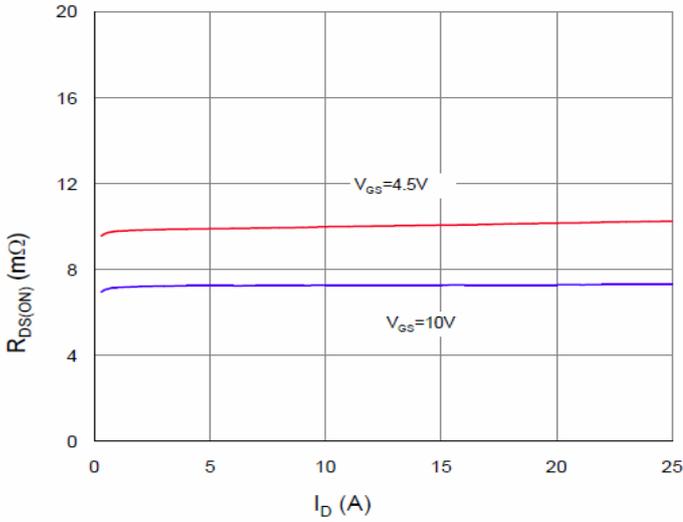


Figure 4. Normalized On-Resistance vs. Junction Temperature

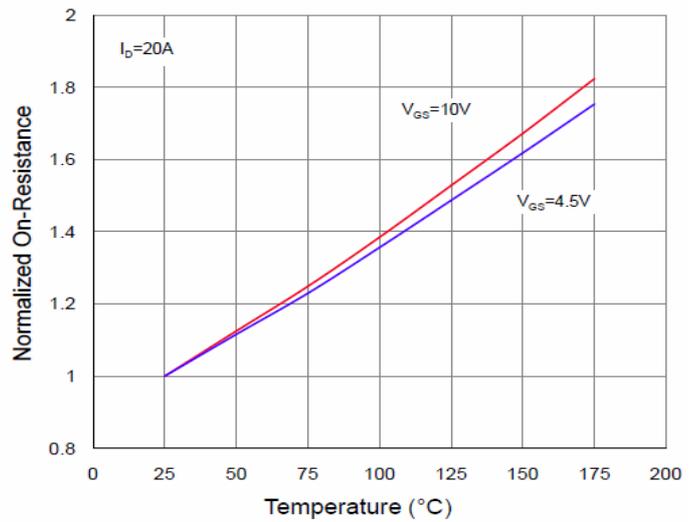


Figure 5. Typical Transfer Characteristics

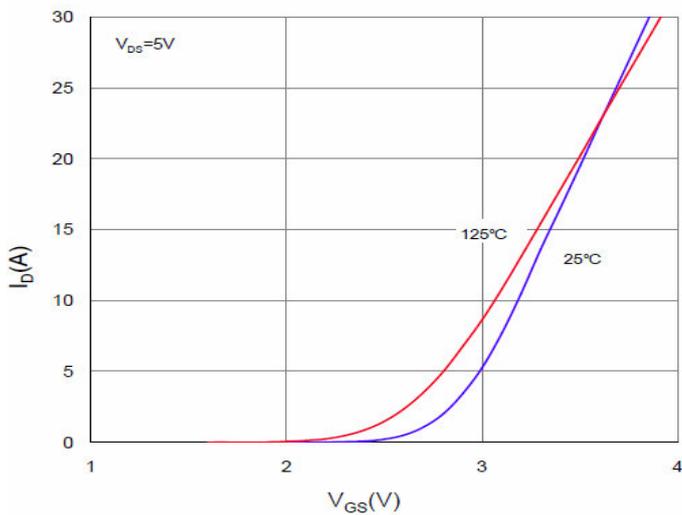
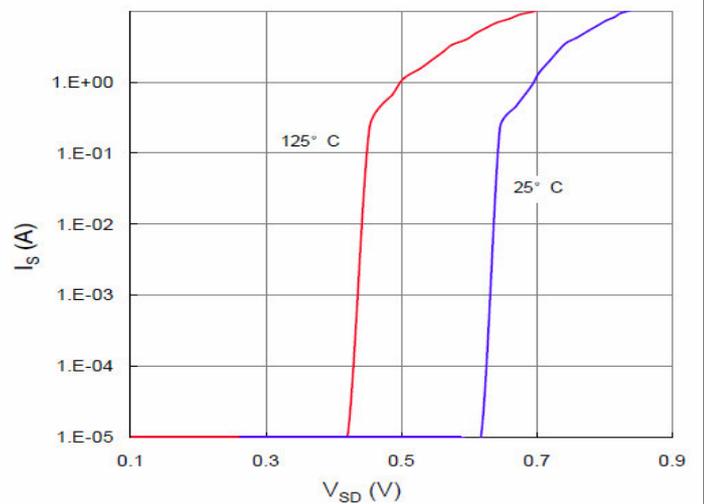


Figure 6. Typical Source-Drain Diode Forward Voltage



CHARACTERISTIC CURVES

Figure 7. Typical Gate-Charge vs. Gate-to-Source Voltage

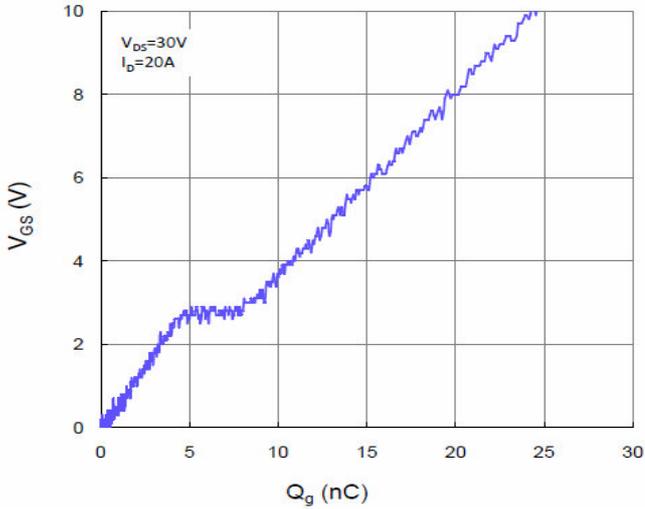


Figure 8. Typical Capacitance vs. Drain-to-Source Voltage

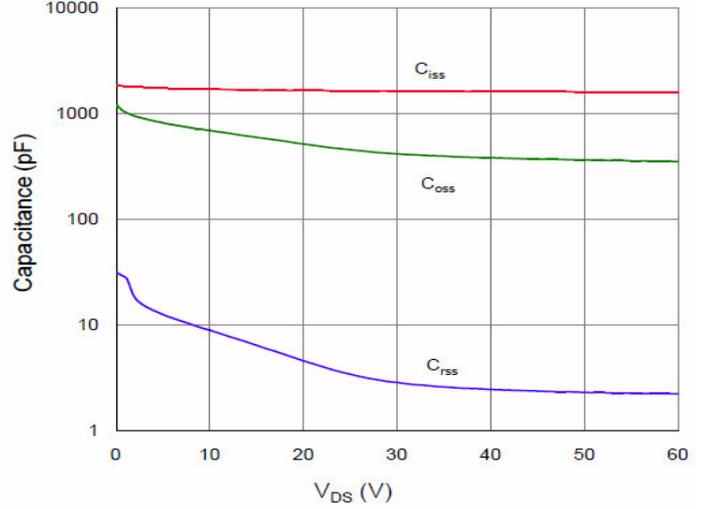


Figure 9. Maximum Safe Operating Area

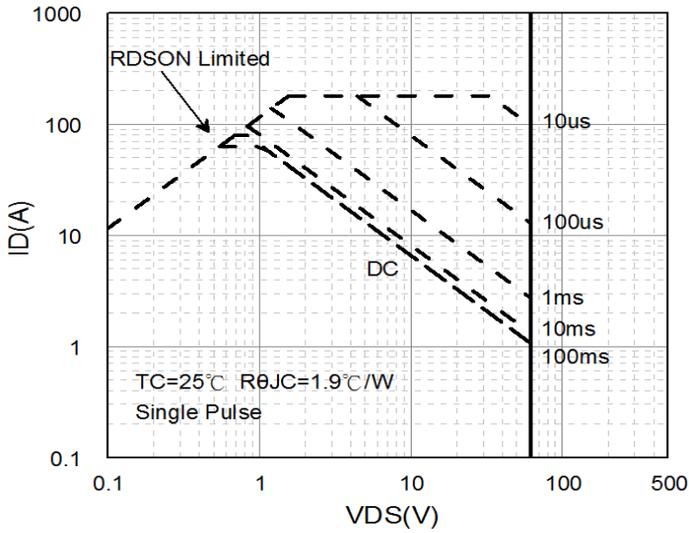


Figure 10. Drain Current vs. Case Temperature

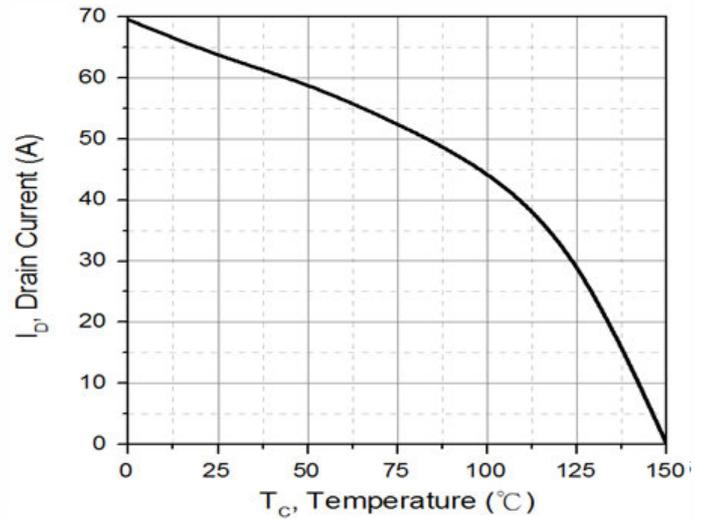


Figure 11. Normalized Maximum Transient Thermal Impedance, Junction-to-Case

